

<b>Notice of References Cited</b>	Application/Control No. 10/524,216	Applicant(s)/Patent Under Reexamination CHOWDHRY ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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*	N	WO 01/44325 A1	06-2001	International	Kristen et al.	C08F 10/02
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